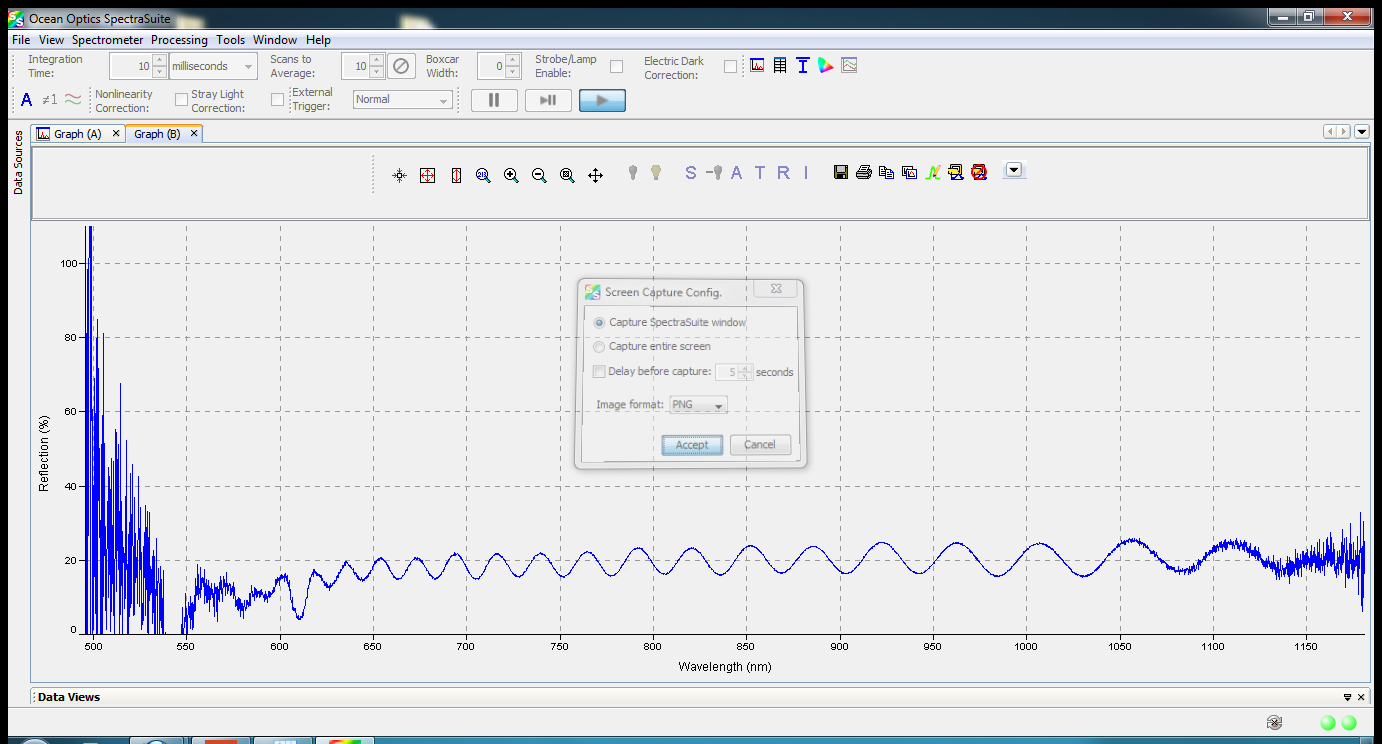
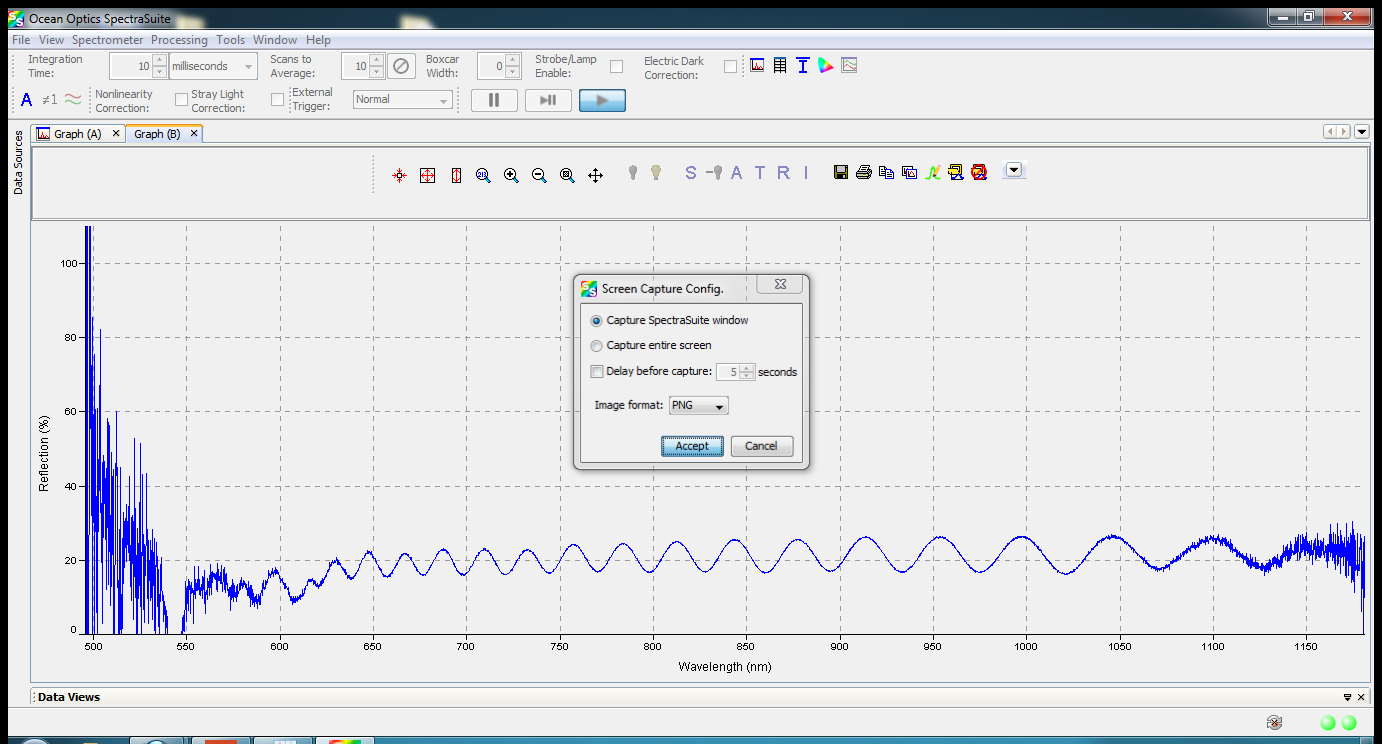
**Screen Captures of Spectrometer Images**

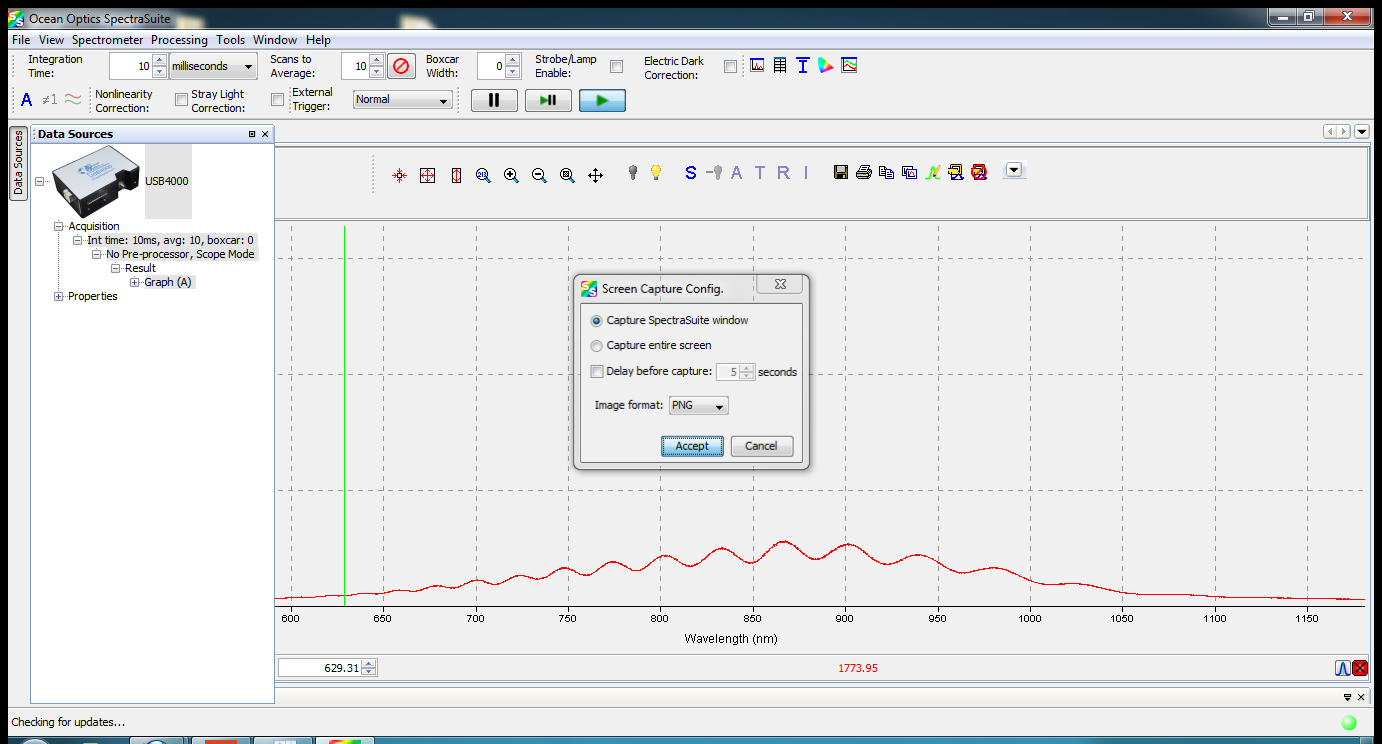
**Below are three screen captures of wavelength vs. percent reflectance graphs. They are examples of the interference pattern produced when a reflectance measurement of a porous silicon film is taken.**



**Figure 1**



**Figure 2**



**Figure 3**

*Images source*: 2013 Caleb Swartz, Vanderbilt University